



**RELIABILITY DATA  
LTC1404  
8/21/2006**

**• OPERATING LIFE TEST**

| PACKAGE TYPE  | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS <sup>(1)</sup> AT +125°C | NUMBER OF <sup>(2)</sup> FAILURES |
|---------------|-------------|------------------|------------------|---|-----------------------------------|
| SOIC/SOT/MSOP | 80<br>80    | 9813             | 9813             | 80.05<br>80.05                          | 0<br>0                            |

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

| PACKAGE TYPE  | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS | NUMBER OF FAILURES |
|---------------|-------------|------------------|------------------|----------------|--------------------|
| SOIC/SOT/MSOP | 50<br>50    | 9739             | 9739             | 1.20<br>1.20   | 0<br>0             |

(1) Assumes Activation Energy = 0.7 Electron Volts  
 (2) Not Enough Data to Predict Failure Rate  
 (3) Refer to Rel Data Pack for Generic Product Family Data  
 Note: 1 FIT = 1 Failure in One Billion Hours.